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U.S. Department of Commerce, Patent and Trademark Office					Docket No. Serial No.						
						2735/PD	С/ЈВ	09/111,454			
LIST OF RELEVANT ART CITED BY APPLICANT						Applicant					
(Use several sheets if necessary)  AUS 1 7 1998 (8)						Ben-Porath et al					
\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\						Filing Date Group					
LLS Patent Documents						July 8, 1998		2723			
			J	J.S. Patent Doc	uments						
*Examiner		Document	Issue		• •			Filing Date In	$\overline{\mathbf{f}}$		
Initial		Number	Date	Name	<u>,                                      </u>	Class	Subclass	Appropriate			
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		OTHER .	ART (Includir	ng Author, Title	, Date, Pe	ertinent Pa	ges, Etc.)				
VB	AR	"Electron Beam Pattern Inspection System Using Digital Image Processing:"; Saitoh et al; J. Vac. Sci Technol B. Vol 4, No. 3 May/June 1986 - Pages 686-691									
VB	AS	"Inspection For Defects of A Mask Containing One- to Submicrometer Patterns Using a Scanning Electron Microscope and Feature Extraction Method"; Y. Goto, et al; J.Vac. Sci. Technol 15 (3)0 May/June 1976; Pages 953-956									
VB	AT	"Studies on an Electron-Beam Mask-defect Inspection System"; Y. Wada et al; J. Vac Sci Technol Vol 19 No. 1 May/June 1981									
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11 12 0	CITATION APPLICA	APPLICANT Ariel Ben-Porath						
	(PTO-1	.449)		FILING DATE July 8, 1998	GROUP - <del>2721</del> 2723			
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EXAMINER'S INITIALS	PATENT NO.	DATE		IAME	CLASS	SUBCLASS	FILI DA	- 11
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VB VB	5,761,064	7/02/98	La et al.					
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U.S. Depart	Commerce, F	Patent and Tra	demark Office	Docket	No.	Serial No.			
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VB	AA	5,862,055	1/19/99	Chen et al			RECEIVE		
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	APPLICA	APPLICANT Ariel Ben-Porath, et al.								
	(PTO-1	(449) OCT	1 9 1999 3040	FILING DATE July 08, 1998	GROUP 2724 2723					
		`W	S. <sub>I</sub> RATÉNT	DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	1	NAME	AME CLASS		FILING DATE			
VB,	5,814,829	9/29/1998	Broude et al	•	1	SUBCLASS				
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VB	EP 0 359 838	3/28/1990	Europe							
VB	WO 97/02465	1/23/1997	PCT			-				
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